



**MICROCHIP**

**QUALIFICATION REPORT  
RELIABILITY LABORATORY**

**PCN#: JAON-25KYQT864**

**Date  
November 24, 2014**

**Qualification of palladium coated copper (PdCu) bond wire at  
MMT assembly site for 120K wafer technology in 14L TSSOP  
package. The 90K and 121K wafer technology and 8L TSSOP  
package will qualify by similarity.**

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## **MICROCHIP**

### **PACKAGE QUALIFICATION REPORT**

<b>Purpose</b>	To qualify 14L TSSOP (4.4mm) package 120K wafer technology using 0.8 mil PdCu wire at MMT (ALPH) Assembly
<b>CN</b>	BC141214
<b>QUAL ID</b>	Q14116
<b>MP CODE</b>	ABBL14D4XA00
<b>Part No.</b>	MCP6234-E/ST
<b>Bonding No.</b>	BDM-000463 Rev. B
<b>CCB No.:</b>	1381.01
<b><u>Package</u></b>	
<b>Type</b>	14L TSSOP
<b>Package size</b>	4.4 mm
<b>Die thickness</b>	11 mils
<b>Die size</b>	53.2 x 43.5 mils
<b><u>Lead Frame</u></b>	
<b>Paddle size</b>	118 x 153 mils (ASM-Singapore)
<b>Material</b>	C7025
<b>Surface</b>	Bare Cu
<b>Process</b>	Stamped
<b>Lead Lock</b>	No
<b>Part Number</b>	10101406
<b>Treatment</b>	BOT
<b><u>Die attach material</u></b>	
<b>Epoxy</b>	2200D (Henkel-Korea)
<b>Wire</b>	PdCu wire (Nippon-Japan)
<b>Mold Compound</b>	G600V (Sumitomo-Singapore)
<b>Plating Composition</b>	Matte Tin



# MICROCHIP PACKAGE QUALIFICATION REPORT


## Manufacturing Information

Assembly Lot No.	Wafer Lot No.	Date Code
MMT-151900011.000	TMPE214499585.300	1432RCK
MMT-151900012.000	TMPE214499585.300	1432RM7
MMT-151800413.000	TMPE214499585.300	1431MJG

### Result

Pass  Fail  \_\_\_\_\_

14L TSSOP (4.4 mm) assembled by MMT (ALPH) pass reliability test per QCI-39000. This package was qualified the Moisture/Reflow Sensitivity Classification Level 1 at 260°C reflow temperature per IPC/JEDEC J-STD-020D standard.

Prepared By:  Date: November 24, 2014 (Sr. Reliability Engineer)

(Mr. Udom Suksansakul)

Approved By:  Date: November 24, 2014 (Reliability Manager)

(Mr. Somnuek Thongprasert)

## PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
<b>Moisture/Reflow Sensitivity Classification Test (At MSL Level 1)</b>	85°C/ 85%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH 3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243  ( IPC/JEDEC J-STD-020D)	IPC/JEDEC C J-STD-020D	135	0/135	Pass	

<b><u>Precondition</u></b> <b><u>Prior Perform</u></b> <b><u>Reliability Tests</u></b> <b>(At MSL Level 1)</b>	<b>Electrical Test</b> :+25°C,85°C and 125°C System: ETS300	JESD22-A113	693(0)	693	Pass	Good Devices
	Bake 150°C, 24 hrs System: CHINEE			693		
	85°C/85%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH			693		
	3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243			693		
	<b>Electrical Test</b> :+25°C and 85°C (With 1 lot 125°C on MMT-151900011.000) System: ETS300			0/693		

# PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
<b>Temp Cycle</b>	<b>Stress Condition:</b> -65°C to +150°C, 500 Cycles System : TABAI ESPEC TSA-70H  <b>Electrical Test: :</b> + 85°C (With 1 lot 125°C on MMT-151900011.000) System: ETS300  <b>Bond Strength:</b> Wire Pull (> 2.5 grams) Bond Shear (>15.00 grams)	JESD22-A104		231		Parts had been pre-conditioned at 260°C 77 units / lot
			231(0)	0/231	Pass	
			15 (0)	0/15	Pass	
			15 (0)	0/15	Pass	
	<b>Stress Condition:</b> -65°C to +150°C, 1000 Cycles System : TABAI ESPEC TSA-70H  <b>Electrical Test: :</b> +85°C (With 1 lot 125°C on MMT-151900011.000) System: ETS300			231		
			231(0)	0/231	Pass	
<b>UNBIASED-HAST</b>	<b>Stress Condition:</b> +130°C/85%RH, 96 hrs. System: HAST 6000X  <b>Electrical Test: :</b> +25°C System: ETS300  <b>Stress Condition:</b> +130°C/85%RH, 192 hrs. System: HAST 6000X  <b>Electrical Test: :</b> +25°C System: ETS300	JESD22-A118		231		Parts had been pre-conditioned at 260°C 77 units / lot
			231(0)	0/231	Pass	
				231		
			231(0)	0/231	Pass	
<b>HAST</b>	<b>Stress Condition:</b> +130°C/85%RH, 96 hrs. <b>Bias Volt: 5.0 Volts</b> System: HAST 6000X  <b>Electrical Test: :</b> +25°C and 85°C (With 1 lot 125°C on MMT-151900011.000) System: ETS300  <b>Stress Condition:</b> +130°C/85%RH, 192 hrs. <b>Bias Volt: 5.0 Volts</b> System: HAST 6000X  <b>Electrical Test: :</b> +25°C and 85°C (With 1 lot 125°C on MMT-151900011.000) System: ETS300	JESD22-A110		231		Parts had been pre-conditioned at 260°C 77 units / lot
			231(0)	0/231	Pass	
				231		
			231(0)	0/231	Pass	

## PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
<b>High Temperature Storage Life</b>	Stress Condition: Bake 175°C, 504 hrs System: SHEL LAB	JESD22- A103		45		45 units
	<b>Electrical Test</b> :+25°C,85°C and 125°C System: ETS300		45(0)	0/45	Pass	
<b>Bond Strength Data Assembly</b>	Wire Pull (> 2.5 grams)	M2011	30 (0) Wires	0/30	Pass	
	Bond Shear (>15.00 grams)	JESD22- B116	30 (0) bonds	0/30	Pass	